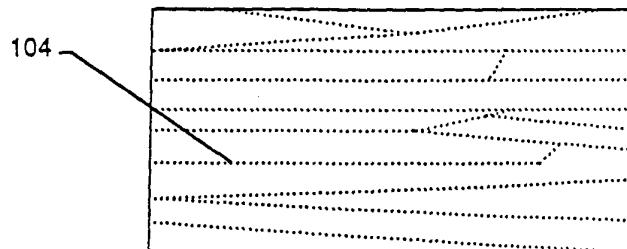


ILLUMINATION WITH
LASER LIGHT OR STRONG LIGHT



Applicant(s): S. Yamazaki et al.
SEMICONDUCTOR THIN FILM AND ITS MANUFACTURING
METHOD AND SEMICONDUCTOR DEVICE AND ITS
MANUFACTURING METHOD

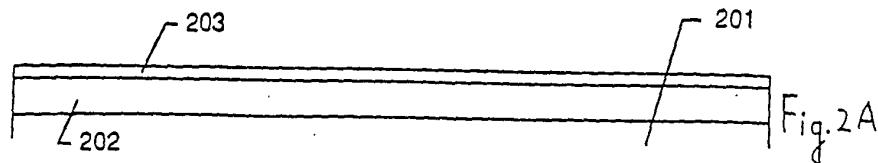


Fig. 2A

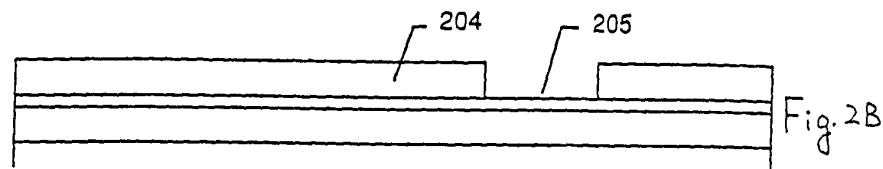


Fig. 2B

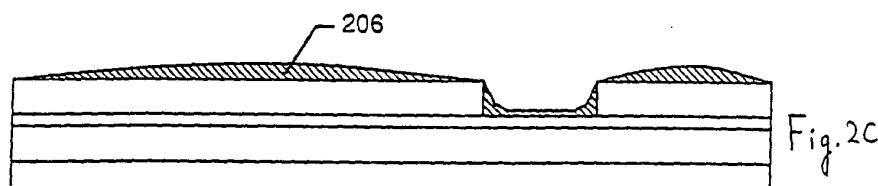


Fig. 2C

HEAT TREATMENT FOR CRYSTALLIZATION

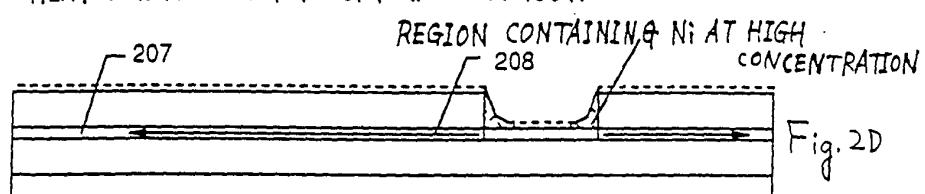


Fig. 2D

ILLUMINATION WITH LASER LIGHT OR STRONG LIGHT

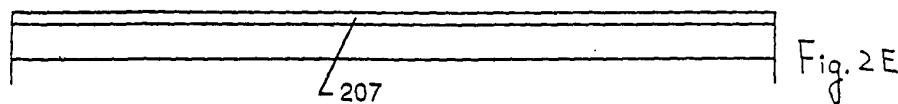


Fig. 2E

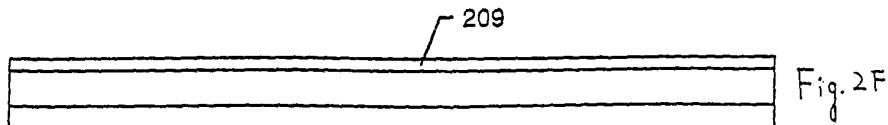
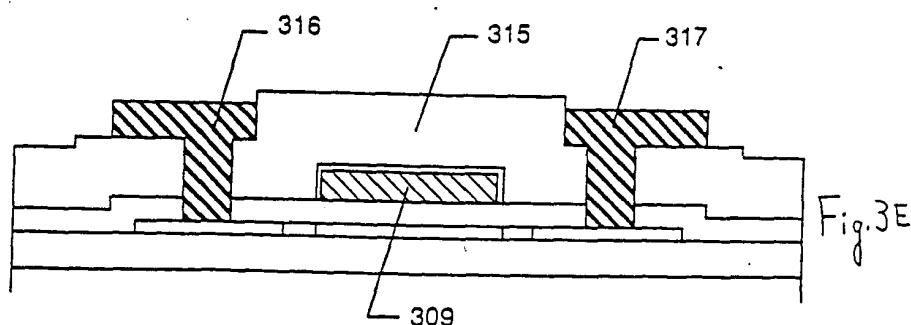
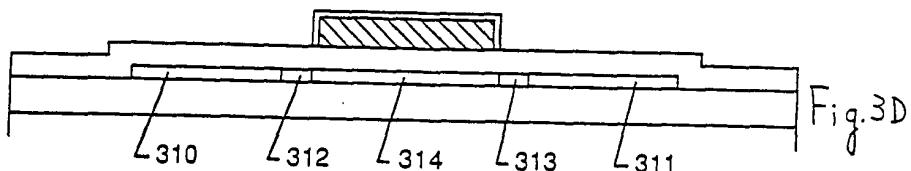
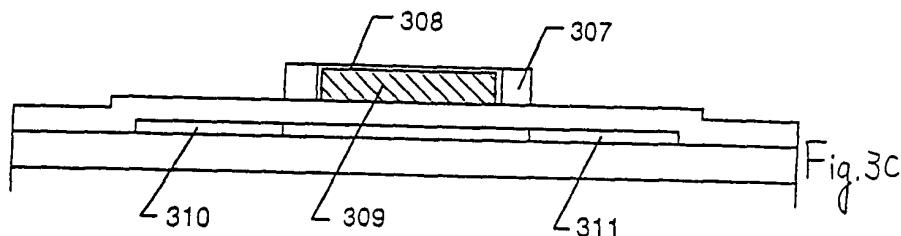
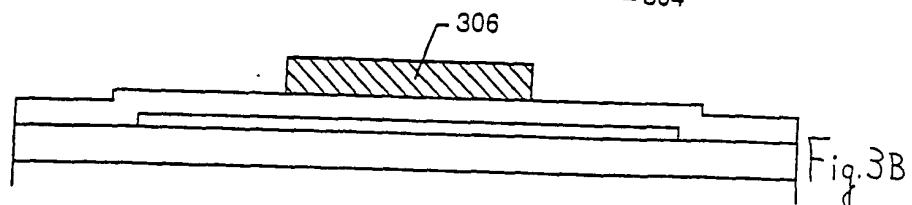
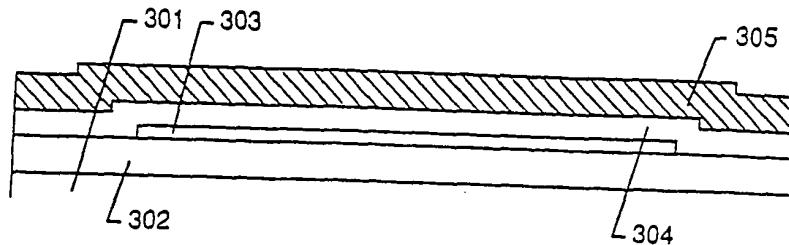


Fig. 2F



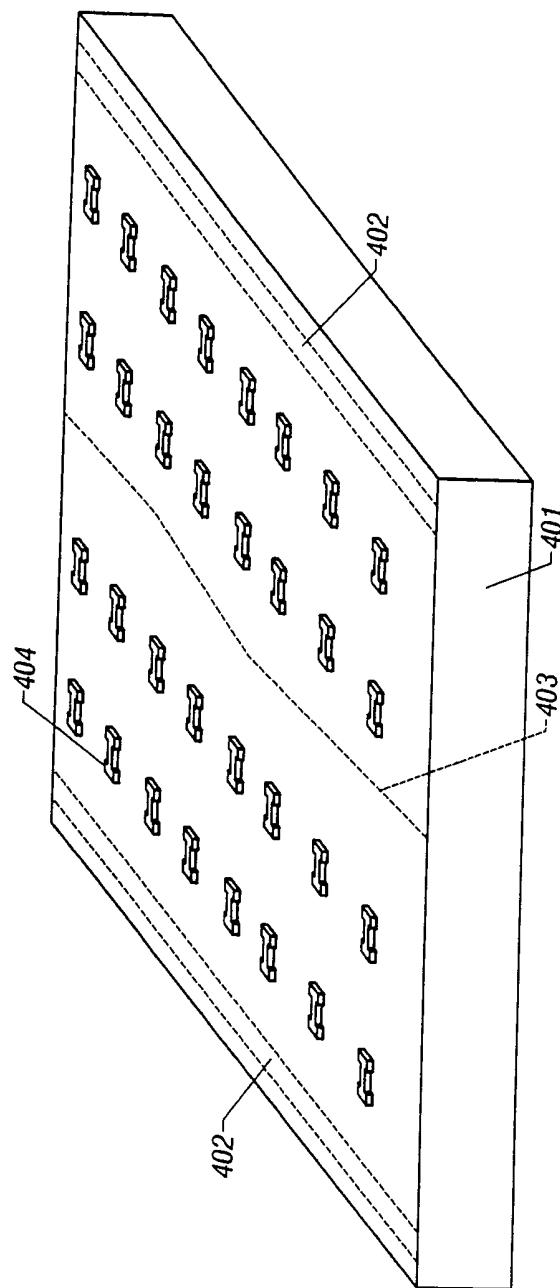


FIG. 4

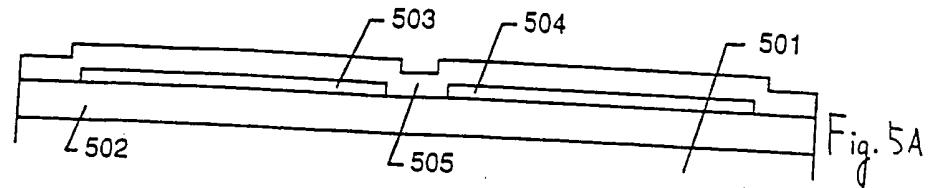


Fig. 5A

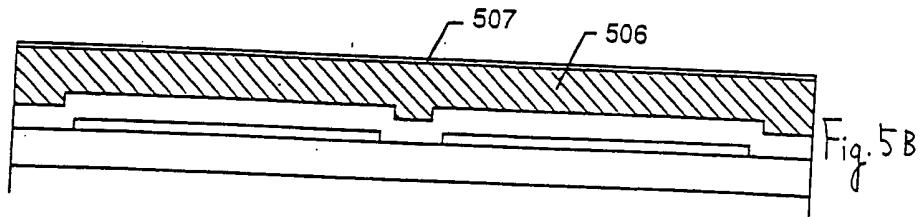


Fig. 5B

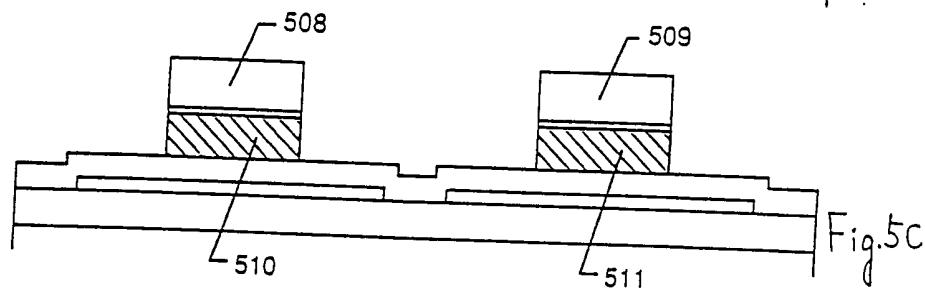


Fig. 5C

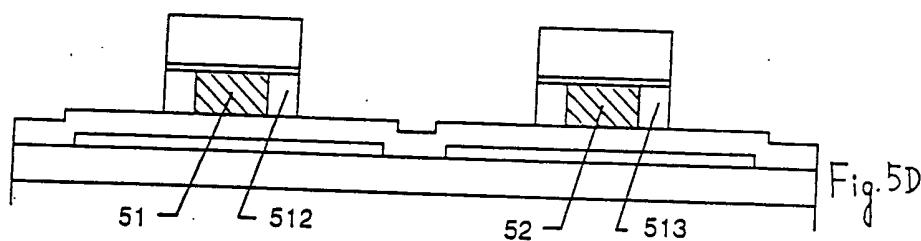


Fig. 5D

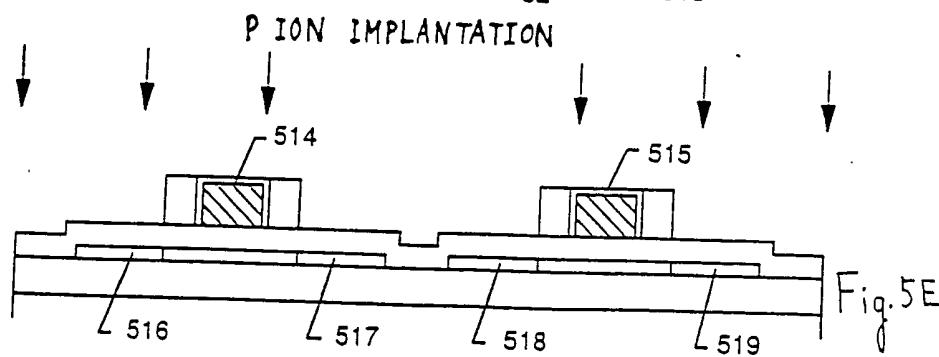
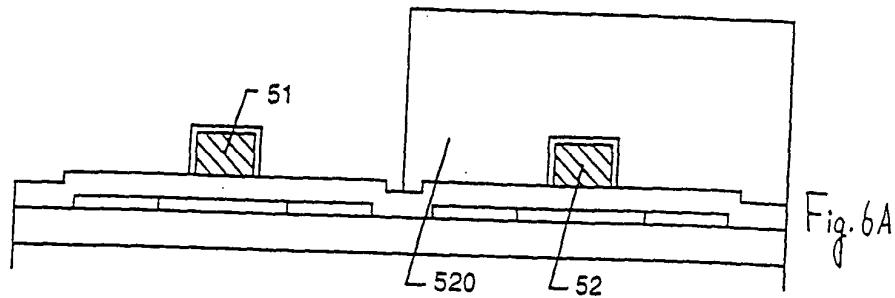
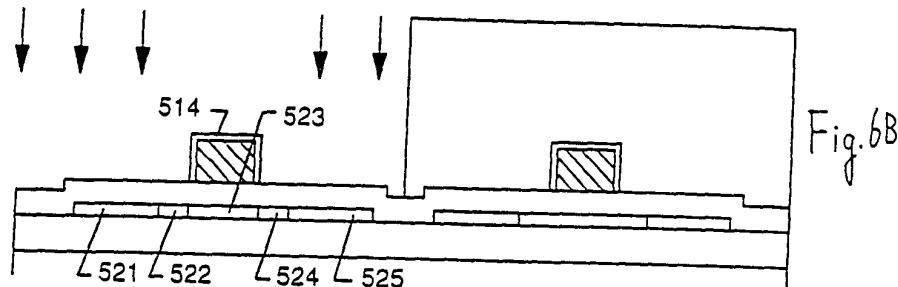


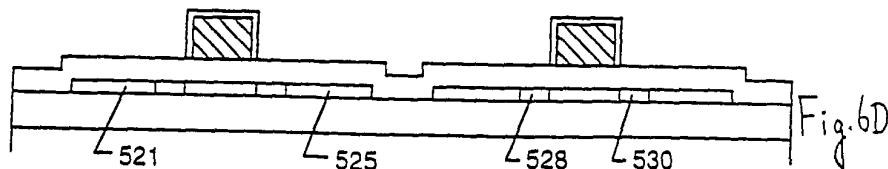
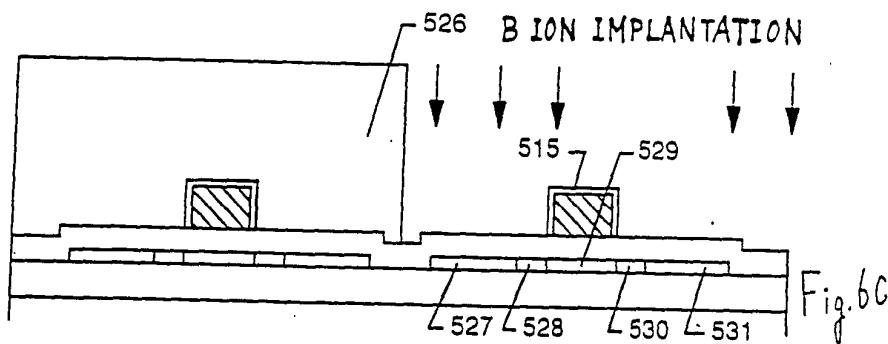
Fig. 5E

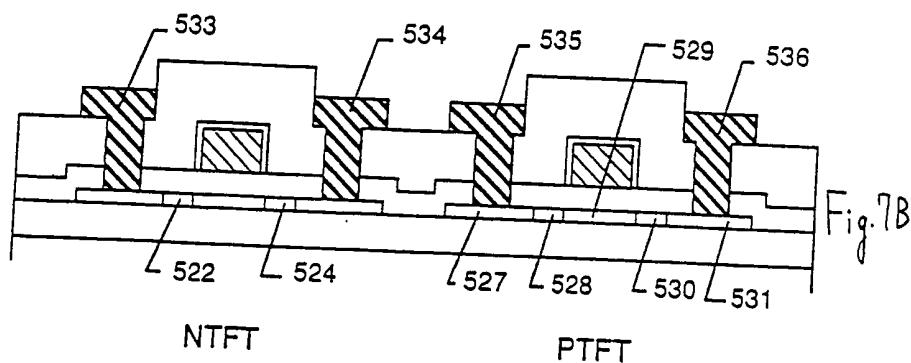
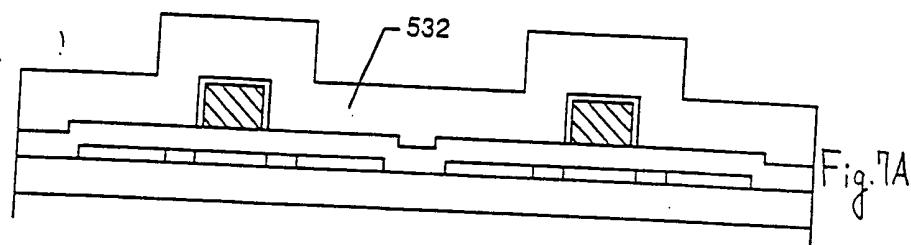


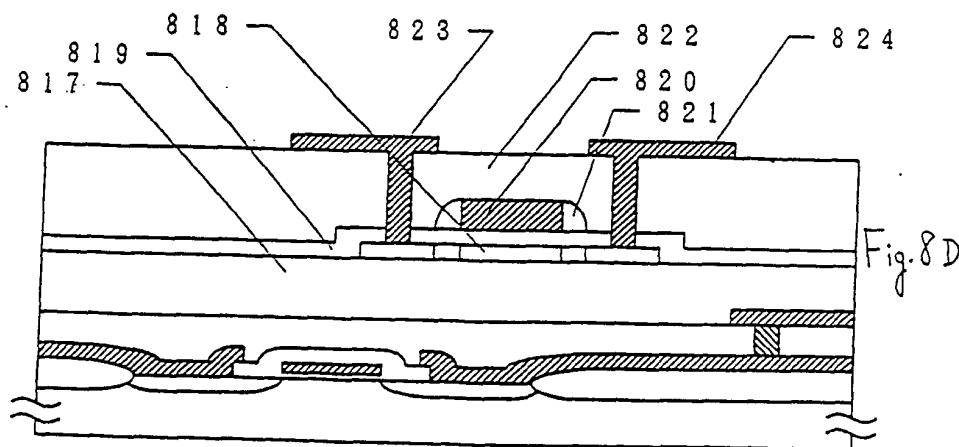
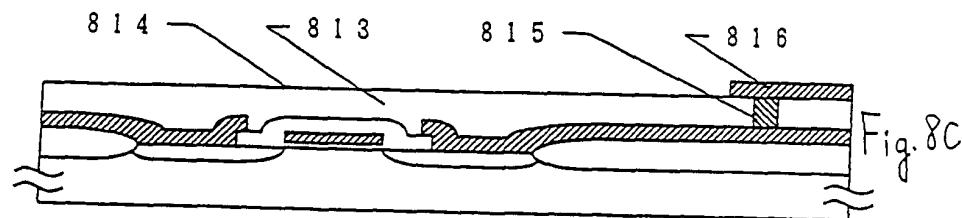
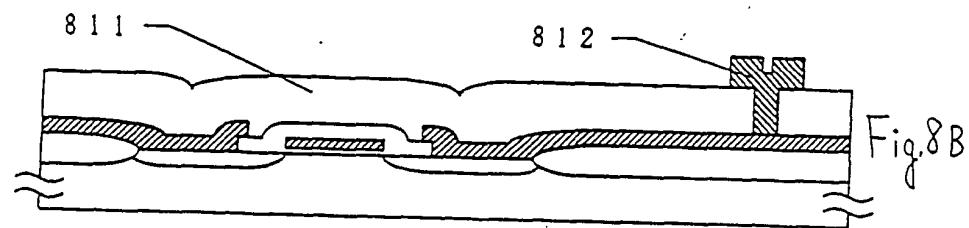
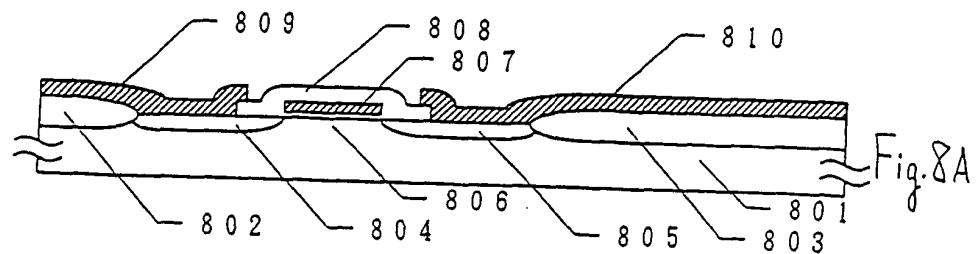
P ION IMPLANTATION



B ION IMPLANTATION







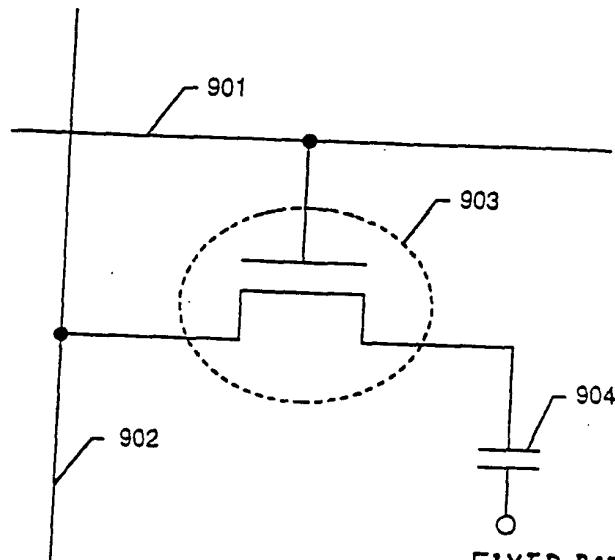


Fig. 9A

FIXED POTENTIAL

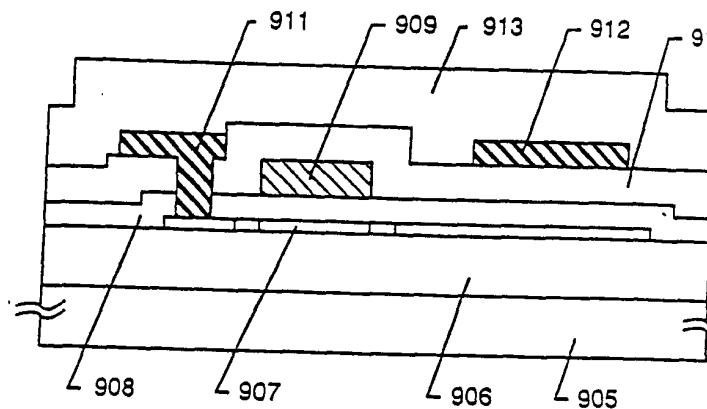


Fig. 9B

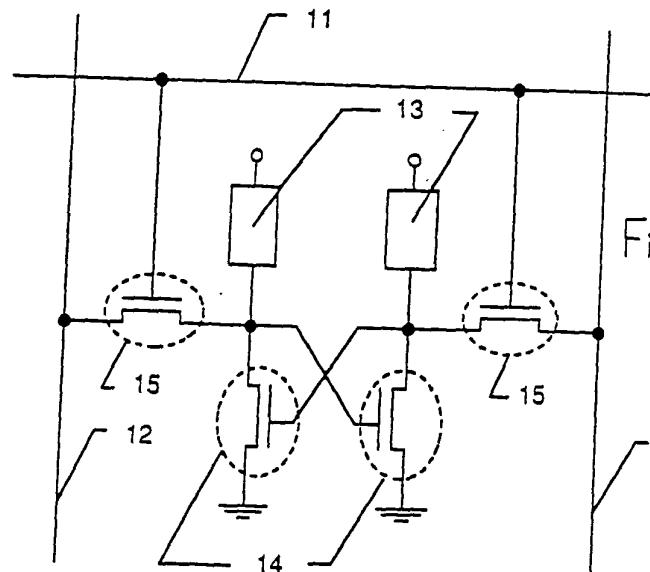


Fig.10A

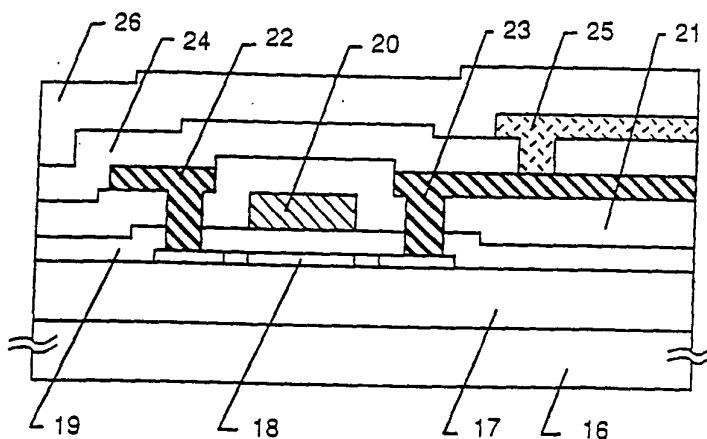


Fig.10B

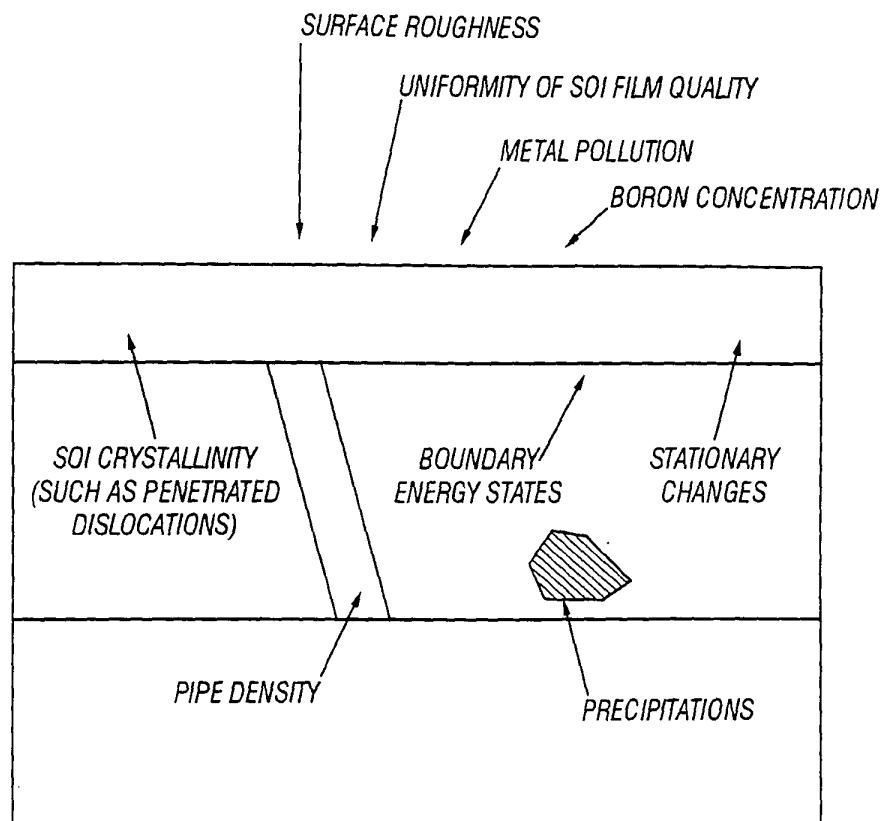


FIG. 11

Applicant(s): S. Yamazaki et al.

SEMICONDUCTOR THIN FILM AND ITS MANUFACTURING
 METHOD AND SEMICONDUCTOR DEVICE AND ITS
 MANUFACTURING METHOD

Fig. 12

ELE-MENT	CONCENTRATION (PPM)	ELE-MENT	CONCENTRATION (PPM)
Fe	0.045	Ca	0.16
Ni	0.016	Mn	<0.001
Na	>0.005	Al	0.004
K	>0.004	U ^{*2}	<0.000031
Ti ^{*1}	<0.05	Th ^{*2}	<0.00016
Mg	>0.005	F ^{*3}	310
Cu	0.009	Cl ^{*2}	<0.73
Cr	0.003	OH ^{*4}	ND

MEASUREMENT METHOD: POLARIZED ZEEMAN FLAMELESS ATOMIC ABSORPTION

NOTES)

*1 ... ICP EMISSION ANALYSIS

*2 ... RADIOACTIVATION ANALYSIS

*3 .. EPMA

*4 ... INFRARED ABSORPTION

Applicant(s): S. Yamazaki et al.

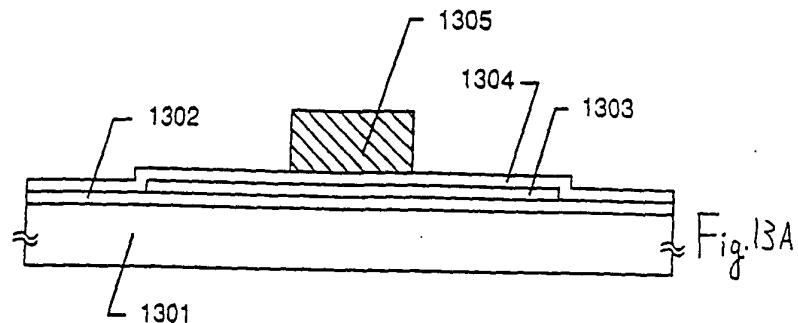
SEMICONDUCTOR THIN FILM AND ITS MANUFACTURING
METHOD AND SEMICONDUCTOR DEVICE AND ITS
MANUFACTURING METHOD

Fig. 13A

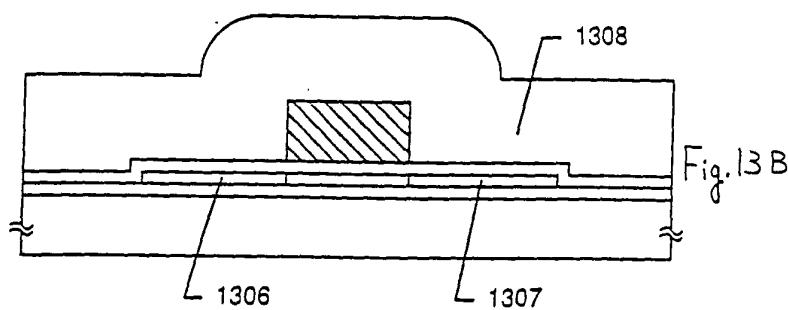


Fig. 13B

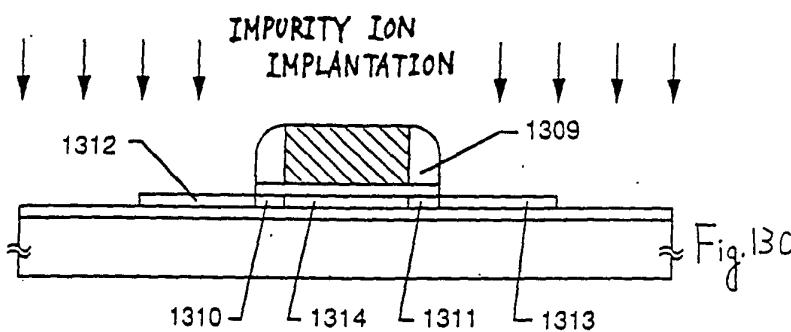


Fig. 13C

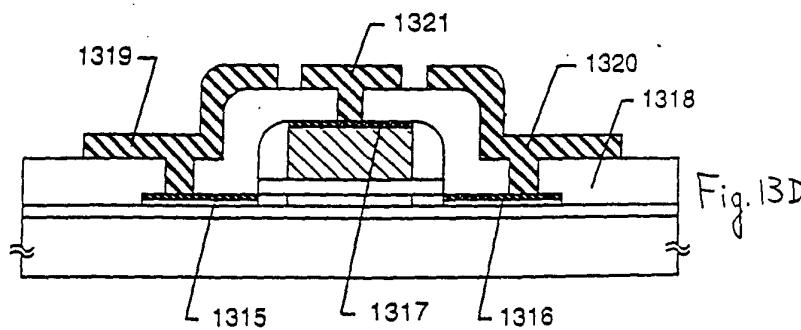


Fig. 13D

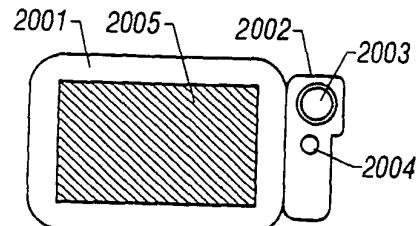


FIG. 14A

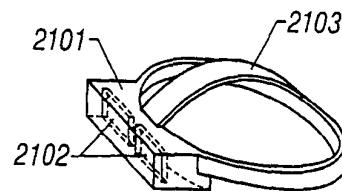


FIG. 14B

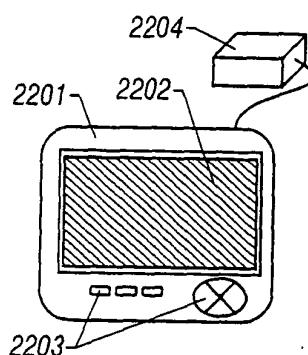


FIG. 14C

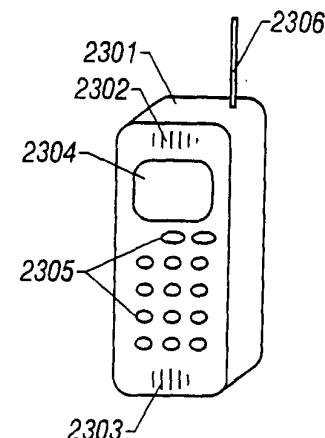


FIG. 14D

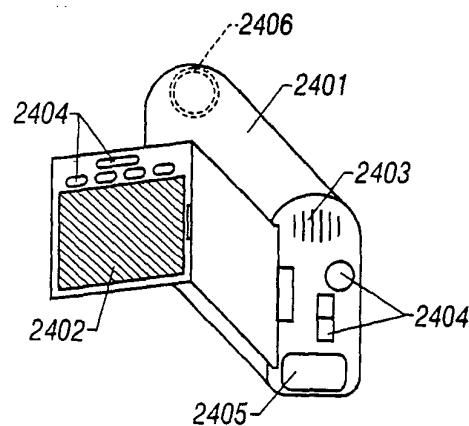


FIG. 14E

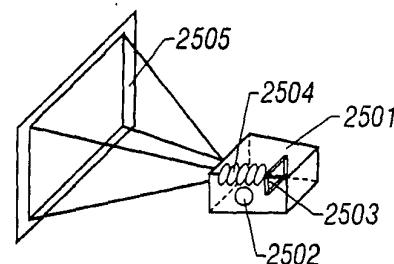


FIG. 14F